

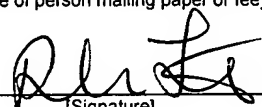
IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Docket No.: VAN HARN

In re Application of:)
EMIEL VAN HARN)
Appl. No.: 10/524,712)
Int. Appl. No.: PCT/EP2003/009460)
Int. Filing Date: August 27, 2003)
For: METHOD FOR MODELLING LIFE OF A)
PIECE OF EQUIPMENT IN AN INDUSTRIAL)
PLANT, METHOD FOR PERFORMING)
MAINTENANCE ON AN INDUSTRIAL)
PLANT AND MAINTENANCE-SYSTEM)

INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Express Mail mailing label number: EV 626144533 US
Date of Deposit: March 10, 2005
I hereby certify that this paper or fee is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10 on the date indicated above and is addressed to "Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450".
ANTONELLA FUSILLO
[Name of person mailing paper or fee]

[Signature]

S I R:

In accordance with 37 C.F.R. 1.56, applicant wishes to call the attention of attention of the Examiner to the references listed on the two enclosed forms PTO-1449 which were cited in the International Search Report issued by the European Patent Office with regard to the corresponding International patent application No. PCT/EP2003/009460. Applicant does not admit that any of the cited documents constitutes prior art against the pending application.

Copies of these references are submitted herewith along with two forms PTO-1449. The Examiner is requested to initial the attached form PTO-1449 and to return a copy of the initialed document to the undersigned as an indication that the attached references have been considered and made of record.

- ☐ This Information Disclosure Statement is filed within three months of the filing date of a national application other than a continued prosecution application under 1.53(d), so that no fee under 37 C.F.R. §1.97 is due.
- ☒ This Information Disclosure Statement is filed within three months of the date of entry of the national stage as set forth in 1.491 in an international application, so that no fee under 37 C.F.R. §1.97 is due.
- ☐ This Information Disclosure Statement is filed before the mailing of a first Office Action on the merits, so that no fee under 37 C.F.R. §1.97 is due.
- ☐ This Information Disclosure Statement is filed before the mailing of a first Office Action after the filing of a request for continued examination under §1.114, so that no fee under 37 C.F.R. §1.97 is due.
- ☐ This Information Disclosure Statement is filed after the issuance of a first office but before issuance of a final action under §1.113, or a notice of allowance under §1.311.
- ☐ This Information Disclosure Statement is submitted after the mailing of a final action or a notice of allowance, but before payment of the issue fee.
- ☐ The undersigned submits the following statement requesting consideration of this statement:

The undersigned hereby states:

- ☐ That each item of information contained in the information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement;
- ☐ That no item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the person signing the statement after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in §1.56(c) more than three months prior to the filing of the information disclosure statement.
- ☐ The fee of \$180.00 set forth in 1.17(p).
- ☐ The Commissioner is hereby authorized to charge the fee as set forth in 1.17(p), and any additional fees which may be required, or credit any overpayment to Deposit Account No. 06-0502.
- ☐ The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment to Deposit Account No. 06-0502.

In order to satisfy the requirement under 37 C.F.R. §1.98(a)(3) for a concise explanation of the relevance of each item of information, applicant herewith submits a copy of the International Search Report.

The above-identified application discloses and claims an invention patentable over this prior art.

Entry of the references above set forth into the file of the above application is believed to be in order and is respectfully requested.

The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment to Deposit Account No. 06-0502.

Respectfully submitted

By: 

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Agent for Applicant
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INFORMATION DISCLOSURE CITATION

Attorney's Docket No. VAN HARN	Applicant EMIEL VAN HARN	Appl. No. 10/524,712
Filing Date	Group	Examiner

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date, if appropriate

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		F.L. Greitzer et al.: "Development of a Framework for Predicting Life of Mechanical Systems: Life Extension Analysis and Prognostics (LEAP)" International Society of Logistics 1999 Symposium, August 30, 1999 – 2 September 1999, pages 1-7, XP002226152, Las Vegas, Nevada, USA
		Nazzari D et al.: "Evaluation of the effectiveness of group screening methods as compared to no group screening", Simulation Conference, 2000. Proceedings. Winter Orlando, FL, USA, 10-13 Dec. 2000, Piscataway, NJ, USA, IEEE, US, December 10, 2000, pages 1499-1504, XP010529703 ISBN: 0-7803-6579-8
		"Reliability Prediction of Board-Mounted Power Modules", Tyco/Electronics Technical Note, 'Online! July 1997, pages 1-6, XP002226153, Retrieved from the Internet: <URL:http://power.tycoelectronics.com>
		Luke S R et al.: "Time meter estimation technique for naval equipment", Reliability and Maintainability Symposium, 1993. Proceedings., Annual Atlanta, GA, USA 26-28 Jan. 1993, New York, NY, USA, IEEE, US, 26 January 1993, pages 10-15, XP010110204, ISBN: 0-7803-0943-X

Examiner:**Date considered:**

*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	Document Number	Date	Country	Class	Subclass	Translation

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		Mettas A et al.: "System reliability analysis: the advantages of using analytical methods to analyze non-repairable systems", 2001 Proceedings of the Annual Reliability and Maintainability Symposium. The International Symposium on Product Quality and Integrity. Rams. Philadelphia, PA, Jan. 22-25, 2001, Annual Reliability and Maintainability Symposium, New York, NY: IEEE, 22 January 2001, pages 80-85, XP010531040, ISBN: 0-7803-6615-8
		Mettas A: "Reliability allocation and optimization for complex systems" Reliability and Maintainability Symposium, 2000. Annual Los Angeles, CA, USA 24-27 Jan. 2000, Piscataway, NJ, USA, IEEE, US, 24 January 2000, pages 216-221, XP010367871, ISBN: 0-7803-5848-1
		Mettas A et al.: "Modeling & Analysis for Multiple Stress-Type Accelerated Life Data", 2002 Proceedings of the Annual Reliability and Maintainability Symposium. The International Symposium on Product Quality and Integrity. Rams. Seattle, WA, Jan. 28-31, 2002, Annual Reliability and Maintainability Symposium, New York, NY: IEEE, US, 28 January 2002, pages 343-348, XP010575849 ISBN: 0-7803-7348-0
		Y. Z. Friedman: "Advanced Control of Ethylene Plants - What works, What doesn't and Why", Hydrocarbon Asia July/August 1999, pages 1-14, XP002247259

Examiner:	Date considered:
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*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.